

PTO/SB/08 Equivalent

<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>	Application No.	10/557,694	
	Filing Date	November 22, 2005	
	First Named Inventor	Hada et al.	
	Art Unit	1795	
	Examiner	Anca Eoff	
(Multiple sheets used when necessary)		Attorney Docket No.	SHIGA7.033APC
SHEET 1 OF 1			

U.S. PATENT DOCUMENTS					
Examiner Initials	Cite No.	Document Number Number - Kind Code (if known) Example: 1,234,567 B1	Publication Date MM-DD-YYYY	Name of Patentee or Applicant	Pages, Columns, Lines Where Relevant Passages or Relevant Figures Appear
/A.E./	1	2002/132181	09-19-2002	Nishimura et al.	
↓	2	2005/95532	05-05-2005	Kodama et al.	
↓	3	2007/65748	03-22-2007	Hada et al.	
↓	4	2001/14428	08-16-2001	Uetani et al.	
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/A.E./	8	JP 2003-287884	10-10-2003	Sumitomo Chem. Co., Ltd.		√
↓	9	JP 2002-145954	05-22-2002	Daicel Chem. Ind. Ltd.		√
↓	10	JP 2003-231673	08-19-2003	Sumitomo Chem. Co., Ltd.		√ abstract
↓	11	JP 2001-183836	07-06-2001	Sumitomo Chem. Co., Ltd.		√ abstract
↓	12	JP 2003-307850	10-31-2003	Fuji Photo Film Co., Ltd.		√
↓	13	JP 10-226658	08-25-1998	Vallee et al.		√ abstract
↓	14	JP 2003-140346	05-14-2003	Mitsubishi Rayon Co., Ltd.		√
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/A.E./	16	EP 982628	03-01-2000	Sumitomo Chem. Co., Ltd.		

NON PATENT LITERATURE DOCUMENTS				
Examiner Initials	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T <sup>1</sup>	
/A.E./	17	PADMANABAN et al, "Performance of Imide and Methide Onium PAGs in 193nm Resist Formulations" Proceedings of SPIE, Vol. 5039, pp. 743-751, (2003).		

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Examiner Signature	/Anca Eoff/	Date Considered	11/12/2008
<p>*Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</p>			

T<sup>1</sup> - Place a check mark in this area when an English language Translation is attached.